Electromagnetic compatibility (EMC) –

Part 4-4: Testing and measurement techniques – Electrical fast transient/burst immunity test

This English-language version is derived from the original bilingual publication by leaving out all French-language pages. Missing page numbers correspond to the French-language pages.
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Part 4-4:
Testing and measurement techniques –
Electrical fast transient/burst immunity test

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-4: Testing and measurement techniques –
Electrical fast transient/burst immunity test

FOREWORD

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International Standard IEC 61000-4-4 has been prepared by sub-committee 77B: High frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

It forms Part 4-4 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107, Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications.


This second edition improves and clarifies simulator specifications, test criteria and test set-ups. Only common mode injection is required.
The text of this standard is based on the following documents:

<table>
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<tr>
<th>FDIS</th>
<th>Report on voting</th>
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<tbody>
<tr>
<td>77B/419/FDIS</td>
<td>77B/424/RVD</td>
</tr>
</tbody>
</table>

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

The contents of the corrigendum of August 2006 and June 2007 have been included in this copy.
INTRODUCTION

IEC 61000 is published in separate parts, according to the following structure:

**Part 1: General**
- General considerations (introduction, fundamental principles)
- Definitions, terminology

**Part 2: Environment**
- Description of the environment
- Classification of the environment
- Compatibility levels

**Part 3: Limits**
- Emission limits
- Immunity limits (in so far as they do not fall under the responsibility of the product committees)

**Part 4: Testing and measurement techniques**
- Measurement techniques
- Testing techniques

**Part 5: Installation and mitigation guidelines**
- Installation guidelines
- Mitigation methods and devices

**Part 6: Generic standards**

**Part 9: Miscellaneous**

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: 61000-6-1).

This part is an international standard which gives immunity requirements and test procedures related to electrical fast transients/bursts.
1 Scope

This part of IEC 61000-4 relates to the immunity of electrical and electronic equipment to repetitive electrical fast transients. It gives immunity requirements and test procedures related to electrical fast transients/bursts. It additionally defines ranges of test levels and establishes test procedures.

The object of this standard is to establish a common and reproducible reference for evaluating the immunity of electrical and electronic equipment when subjected to electrical fast transient/bursts on supply, signal, control and earth ports. The test method documented in this part of IEC 61000-4 describes a consistent method to assess the immunity of an equipment or system against a defined phenomenon.

NOTE As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

The standard defines:
- test voltage waveform;
- range of test levels;
- test equipment;
- verification procedures of test equipment;
- test set-up;
- test procedure.

The standard gives specifications for laboratory and post-installation tests.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.